

#### **Features**

- Split Gate Trench MOSFET technology
- Excellent package for heat dissipation
- High density cell design for low RDS(ON)

## **Product Summary**



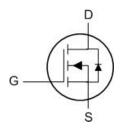
BVDSS	RDSON	ID
100V	15.6mΩ	12A

## **Applications**

- DC-DC Converters
- Power management functions
- Synchronous-rectification applications

## GCD, 'D]b'7cb2[[ifUt]cb'





## **Absolute Maximum Ratings**

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	100	V
V <sub>G</sub> S	Gate-Source Voltage	±20	V
I <sub>D</sub> @T <sub>C</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1,6</sup>	12	Α
I <sub>D</sub> @T <sub>C</sub> =100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1,6</sup>	9	А
I <sub>DM</sub>	Pulsed Drain Current <sup>2</sup>	60	Α
EAS	Single Pulse Avalanche Energy <sup>3</sup>	80	mJ
las	Avalanche Current		А
P <sub>D</sub> @T <sub>C</sub> =25°C	Total Power Dissipation <sup>4</sup>	60	W
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

### **Thermal Data**

Symbol	Parameter		Max.	Unit
Reja	Thermal Resistance Junction-Ambient <sup>1</sup>		52	°C/W
Rejc	Thermal Resistance Junction-Case <sup>1</sup>		1.75	°C/W



## Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	100			V
$\triangle BV_{DSS}/\triangle T_{J}$	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =1mA				V/°C
D Statio Drain Source On	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V , I <sub>D</sub> =5A		15.6	19.5	mΩ
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS}$ =4.5 $V$ , $I_D$ =4 $A$		18.6	23.2	
V <sub>GS(th)</sub>	Gate Threshold Voltage	\/=\/	1.3	1.8	2.3	V
$\Delta V_{GS(th)}$	V <sub>GS</sub> =V <sub>DS</sub> . I <sub>D</sub> =250uA					mV/°C
la sa	Drain-Source Leakage Current	V <sub>DS</sub> =100V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	
I <sub>DSS</sub>	Dialii-Source Leakage Current	V <sub>DS</sub> =100V, V <sub>GS</sub> =0V , T <sub>J</sub> =100°C			100	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}=\pm 20V$ , $V_{DS}=0V$			±100	nA
gfs	fs Forward Transconductance V <sub>DS</sub> =10V , I <sub>D</sub> =10A			54		S
R <sub>g</sub>	R <sub>g</sub> Gate Resistance V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz			1.8		Ω
$Q_g$	Total Gate Charge			22.7		
Q <sub>gs</sub>	Gate-Source Charge	V <sub>DS</sub> =50V , V <sub>GS</sub> =10V , I <sub>D</sub> =10A		3		nC
$Q_{gd}$	Gate-Drain Charge			5		
T <sub>d(on)</sub>	Turn-On Delay Time			9.2		
Tr	Rise Time	VGS=10V, VDD=50V,		3.6		
T <sub>d(off)</sub>	Turn-Off Delay Time	RG=3Ω, ID=10A		25.6		ns
T <sub>f</sub>	Fall Time			4.4		
C <sub>iss</sub>	Input Capacitance			1208		
Coss	Output Capacitance	V <sub>DS</sub> =50V , V <sub>GS</sub> =0V , f=1MHz		144		pF
$C_{rss}$	Reverse Transfer Capacitance			11.3		

#### **Diode Characteristics**

Symbol	Parameter Conditions		Min.	Тур.	Max.	Unit
ls	Continuous Source Current <sup>1,4</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			12	Α
VsD	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =20A , T <sub>J</sub> =250			1.2	V
t <sub>rr</sub>	Reverse Recovery Time	IF=10A , di/dt=100A/μs ,				nS
Q <sub>rr</sub>	Reverse Recovery Charge	T <sub>J</sub> =250				nC

FÈ he Ádata Á ested Ány Ásurface Ámounted Án Ás Á Ánch² FR-4 Ánoard Á with Á2 OZ Ásopper.

CH he Átata Áested ÁbyÁbulsedÁbulse Ávidth Á 300us Áðiuty Ásycle Á 2%. HE he EAS data shows Max. rating . The test condition is VRA/AG »Ô,VDD=50V,VGS=10V,L=0.1mH. I È he Ábower Álissipation Ás Áimited ÁbyÁ 50°C junction Áemperature I E he data is theoretically the same as I<sub>D</sub>and I<sub>DMA</sub> in real applications Áshould Ábe Áimited ÁbyÁotal Ábower Átissipation.



# **Typical Characteristics**

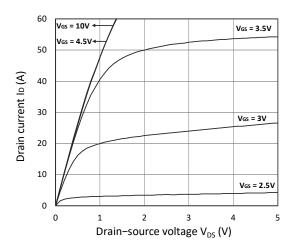


Figure 1. Output Characteristics

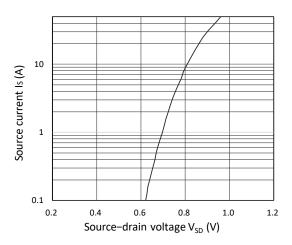


Figure 3. Forward Characteristics of Reverse

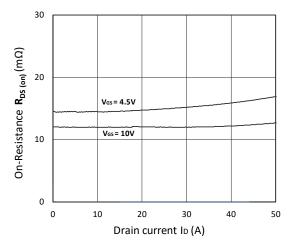


Figure 5.  $R_{DS(ON)}$  vs.  $I_D$ 

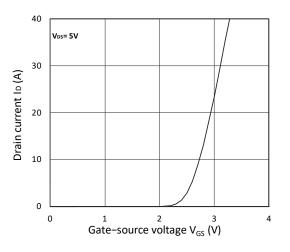


Figure 2. Transfer Characteristics

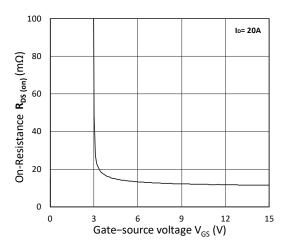


Figure 4.  $R_{DS(ON)}$  vs.  $V_{GS}$ 

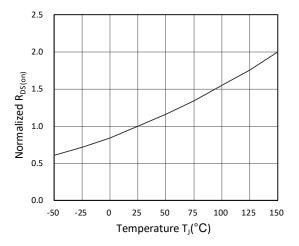


Figure 6. Normalized  $R_{\text{DS(on)}}$  vs. Temperature



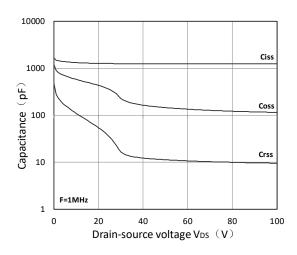


Figure 7. Capacitance Characteristics

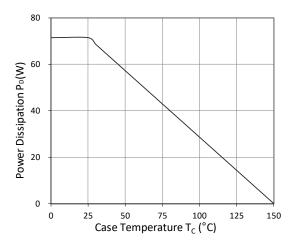


Figure 9. Power Dissipation

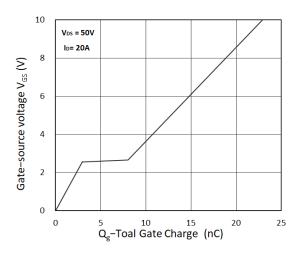


Figure 8. Gate Charge Characteristics

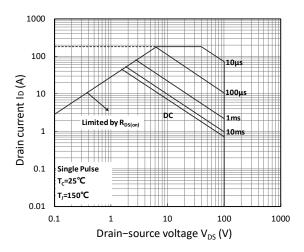


Figure 10. Safe Operating Area

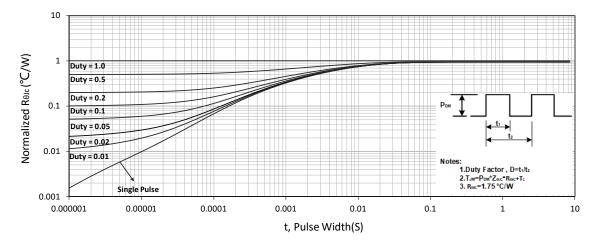
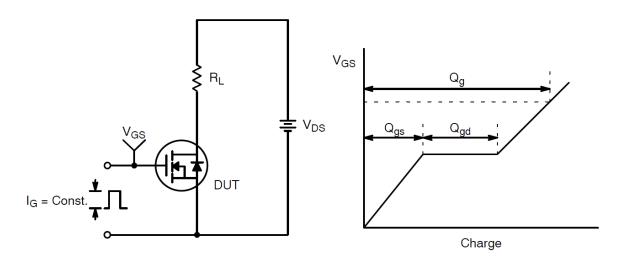


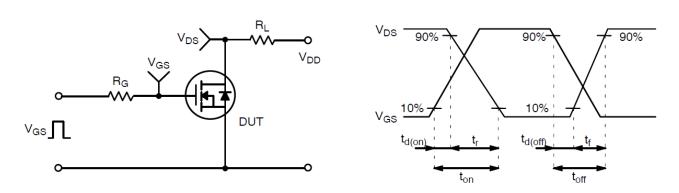
Figure 11. Normalized Maximum Transient Thermal Impedance



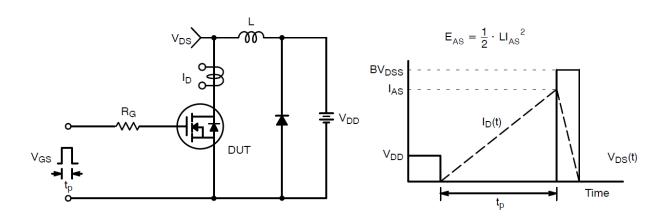
# **Test Circuit and Waveform:**



**Gate Charge Test Circuit & Waveform** 



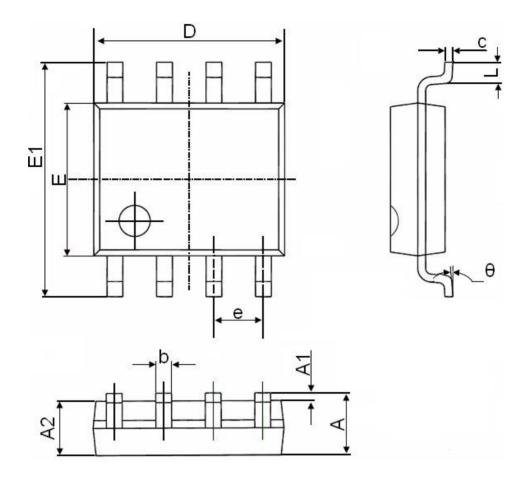
# **Resistive Switching Test Circuit & Waveforms**



**Unclamped Inductive Switching Test Circuit & Waveforms** 



# **SOP-8 Package Information**



Symbol	Dimensions In Millimeters		Dimensions In Inches		
	Min.	Max.	Min.	Max.	
Α	1.350	1.750	0.053	0.069	
A1	0.100	0.250	0.004	0.010	
A2	1.350	1.550	0.053	0.061	
b	0.330	0.510	0.013	0.020	
С	0.170	0.250	0.006	0.010	
D	4.700	5.100	0.185	0.200	
E	3.800	4.000	0.150	0.157	
E1	5.800	6.200	0.228	0.244	
е	1.270(BSC)		0.050(BSC)		
L	0.400	1.270	0.016	0.050	
θ	0°	8°	0°	8°	